



60/2823

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of  
Tsung et al.

Atty. Docket: TI-30243

Serial No.: 09/921,324

Art Unit: 2823

Filed: August 2, 2001

Examiner: G. Fourson III

Title: Mass Production of Cross-Section TEM Samples by  
Focused Ion Beam Deposition and Anisotropic Etching

Amendment-A Under 37 CFR 1.111

Assistant Commissioner of Patents  
Washington, DC 20231

MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(a)  
I hereby certify that the above  
correspondence is being deposited with the  
U.S. Postal Service with sufficient postage  
for First Class mail in an envelope addressed  
to: Assistant Commissioner for Patents,  
Washington D.C. 20231 on:

3-20-03

Jackie McBride  
Jackie McBride

Dear Sir:

Responsive to Examiner's Office Action dated December  
20, 2002, Applicants amend the application as follows:

RECEIVED  
MAR 27 2003  
TECHNICAL STAFF 2800